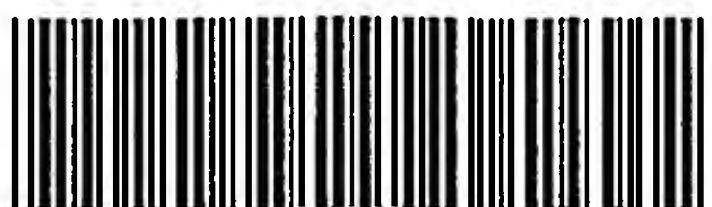


## **Search Notes**



**Application/Control No.**

10/708.305

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**Examiner**

Steven M. Marsh

**Applicant(s)/Patent under  
Reexamination**

LEE, TIEK-NYEN

## Art Unit

3632

**SEARCHED**

# SEARCH NOTES (INCLUDING SEARCH STRATEGY)

## INTERFERENCE SEARCHED

<b>INTERFERENCE SEARCHED</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>